

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): S. YAMAZAKI, et al.

Group Art Unit: 2872

Serial No.: 10/823,020

Examiner: T/B/A

Filed: April 12, 2004

For: SCANNING OPTICAL SYSTEM

INFORMATION DISCLOSURE STATEMENT

Mail Stop _____
Commissioner for Patents
P.O. Box 1450
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Sir:

Pursuant to Rule 56, applicant hereby calls the attention of the Patent Office to the references listed on the attached Form PTO 1449. Copy(ies) of these references ☒ are attached ☐ were filed in related application U.S. Serial No(s) _____, filed _____, respectively.

- ☐ This document is being filed within three (3) months of the filing date of the application
- ☐ A check for the requisite fee of \$180 is enclosed.
- ☐ This document is being concurrently filed with the above-identified application
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- ☒ This document is accompanied by a Search Report/Communication cited in a corresponding PCT or foreign counterpart application.
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Respectfully submitted,
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Dated: September 15, 2004By: 

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FORM PTO-1449

INFORMATION DISCLOSURE CITATION

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10/823,020Applicant:
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2872

U.S. PATENT DOCUMENTS

Examiner Initial		Patent Number	Publication Date	Name	Class	Sub-Class	Filing Date
	AA	6,222,676	04-24-2001	Togino, et al.			
	AB	6,333,820	12-25-2001	Hayakawa, et al			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

Examiner Initial		Patent Number	Publication Date	Country	Class	Sub-Class	Translation
	AL	DE 10127367	12-12-2002	Germany			Abstract
	AM	EP 1 225 470	12/12/2001	Europe			<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
	AN	JP 2003029197	01-29-03	Japan			Abstract
	AO						<input type="checkbox"/> Yes <input type="checkbox"/> No
	AP						<input type="checkbox"/> Yes <input type="checkbox"/> No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Papers, etc.)

	AR	
	AS	
	AT	

Examiner

Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609.
Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to Applicant.